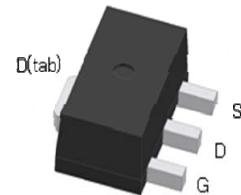
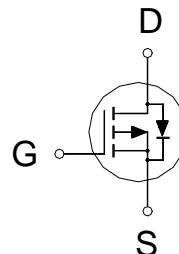


P-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV <sub>DSS</sub>	-30V
R <sub>DSON</sub> (MAX.)	20mΩ
I <sub>D</sub>	-8A



Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNIT
Gate-Source Voltage	V <sub>GS</sub>	±25	V
Continuous Drain Current	I <sub>D</sub>	-8	A
		-6	
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	-32	
Power Dissipation	P <sub>D</sub>	1.47	W
		0.58	
Operating Junction & Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	18	85	°C / W
Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>			

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

<sup>3</sup>85°C / W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.5	-3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
		$V_{DS} = 0V, V_{GS} = \pm 25V$			$\pm 500$	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V$			-1	$\mu\text{A}$
		$V_{DS} = -20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = -5V, V_{GS} = -10V$	-18			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = -10V, I_D = -8A$		17.5	20	$\text{m}\Omega$
		$V_{GS} = -4.5V, I_D = -5A$		26	35	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -5V, I_D = -8A$		24		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1\text{MHz}$		1407		
Output Capacitance	$C_{oss}$			208		pF
Reverse Transfer Capacitance	$C_{rss}$			164		
Gate Resistance	$R_g$	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		4.7		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g(V_{GS}=10V)$	$V_{DS} = -15V, V_{GS} = -10V, I_D = -8A$		20.3		nC
	$Q_g(V_{GS}=4.5V)$			9.8		
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			3.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			4.9		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DS} = -15V, I_D = -1A, V_{GS} = -10V, R_{GS} = 2.7\Omega$		10		nS
Rise Time <sup>1,2</sup>	$t_r$			8		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$			25		
Fall Time <sup>1,2</sup>	$t_f$			6		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$	$I_F = I_S \text{ A}, V_{GS} = 0V$			-3.5	A
Pulsed Current <sup>3</sup>	$I_{SM}$				-14	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S \text{ A}, V_{GS} = 0V$			-1.2	V
Reverse Recovery Time	$t_{rr}$	$I_F = I_S, dI_F/dt = 100\text{A} / \mu\text{s}$		32		nS
Reverse Recovery Charge	$Q_{rr}$			26		

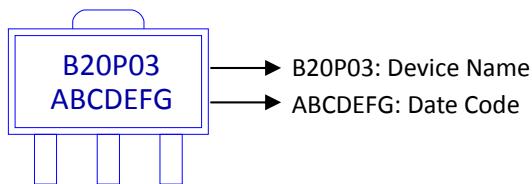
<sup>1</sup>Pulse test : Pulse Width  $\leq$  300  $\mu$ sec, Duty Cycle  $\leq$  2%.

<sup>2</sup>Independent of operating temperature.

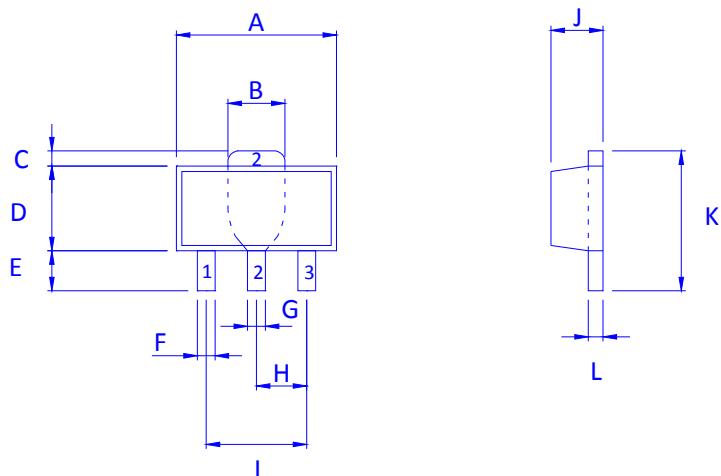
<sup>3</sup>Pulse width limited by maximum junction temperature.

#### Ordering & Marking Information:

Device Name: EMB20P03P for SOT-89



#### Outline Drawing



#### Dimension in mm

Dimension	A	B	C	D	E	F	G	H	I	J	K	L
in.	4.30	1.60	0.40	2.40	0.80	0.40	0.40	1.40	2.80	1.30	3.80	0.30
Typ.												
Max.	4.70	1.80	0.60	2.60	1.40	0.50	0.60	1.60	3.20	1.70	4.60	0.50

#### Footprint

